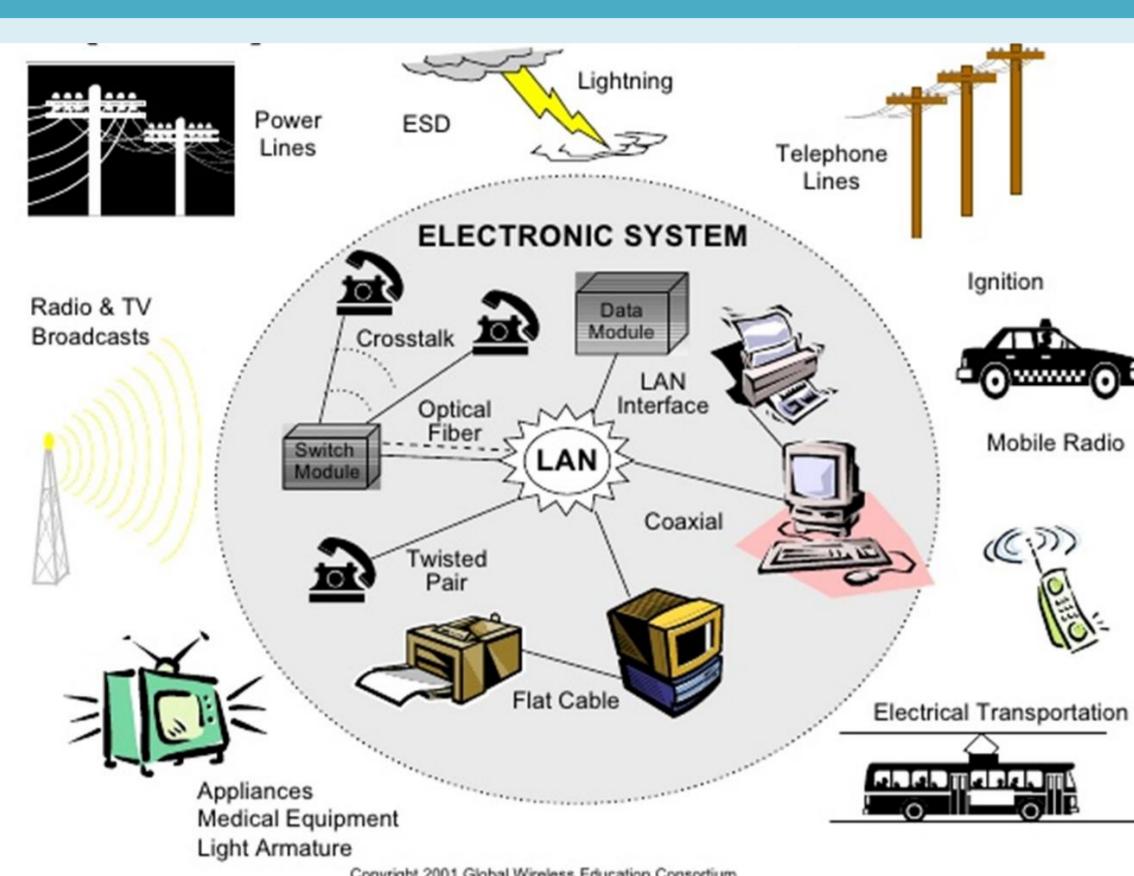


# Electromagnetic Properties of Carbon based Polymer Nanocomposites for Shielding, Chaffing and Camouflage Applications



Joseph Vimal Vas, High Voltage Engineering Lab, Indian Institute of Science, Bengaluru

## Electromagnetic Interference (EMI)



- Modes of noise coupling
  - Conductive coupling
  - Common impedance coupling
  - Coupling via Electric and Magnetic fields
- Methods to reduce EMI
  - Shielding
  - Balancing
  - Filtering
  - Grounding

EMI induces noise in electronic systems

## Electromagnetic Shielding

Materials interact with EM waves through:

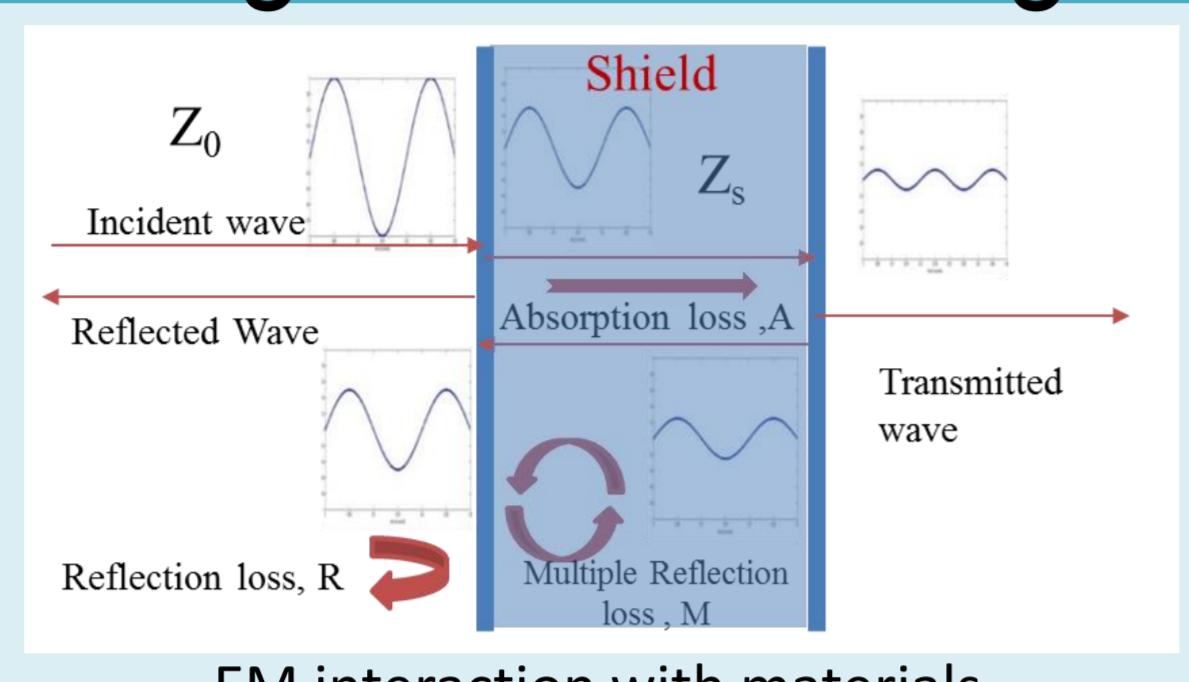
- Reflection
- Absorption
- Multiple reflections

Requirements of a good shield

- High conductivity
- High permittivity
- High permeability

Commercial Shielding Materials

- Highly Conducting Materials- Copper, Aluminium, Stainless Steel
- Shielding mainly through reflection



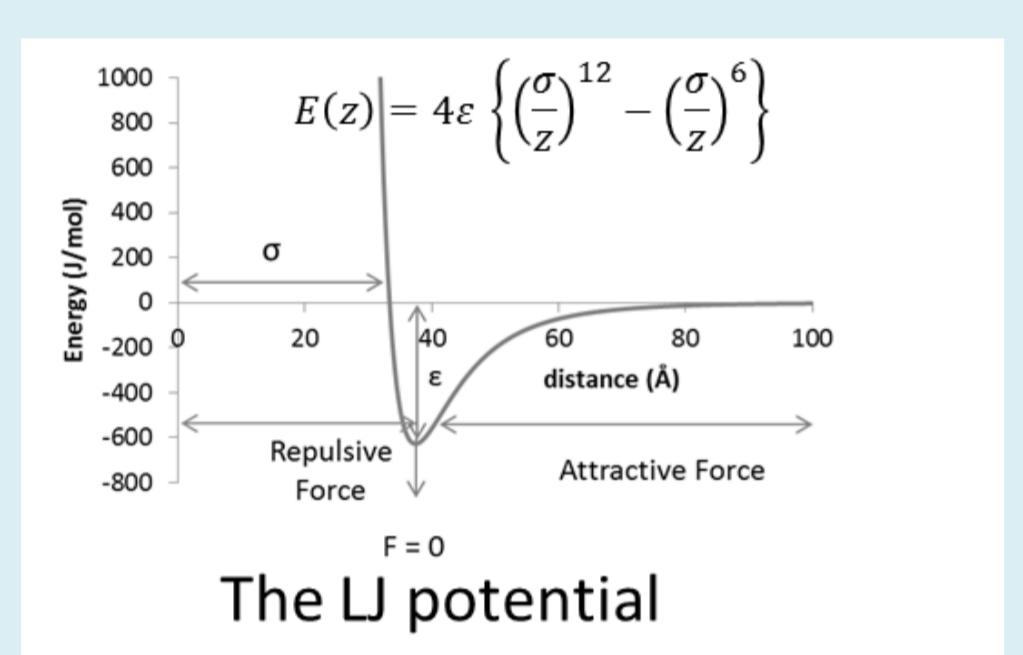
EM interaction with materials



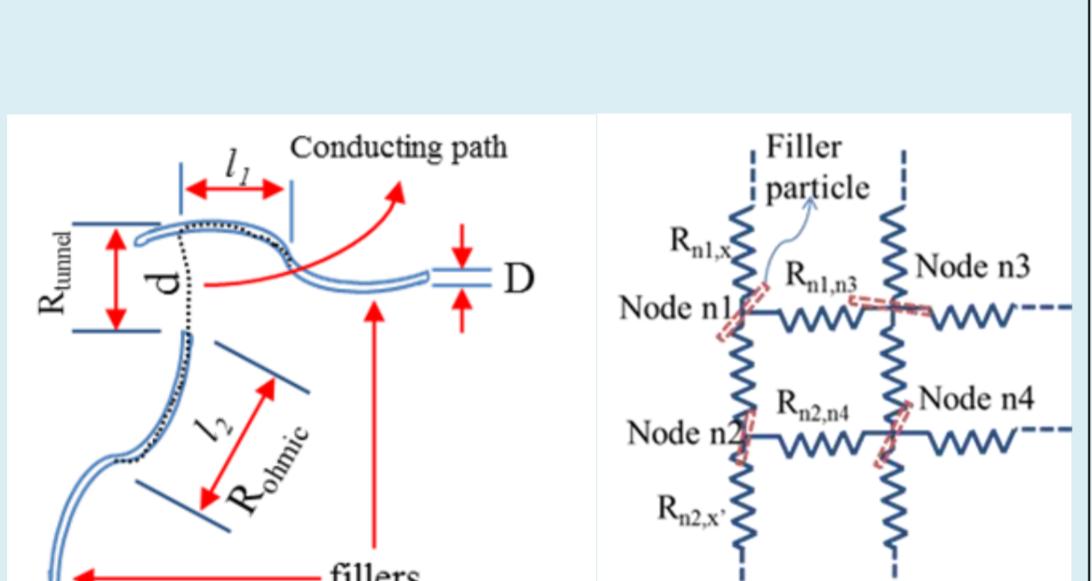
Casing of sensitive electronics

## Monte Carlo Simulations

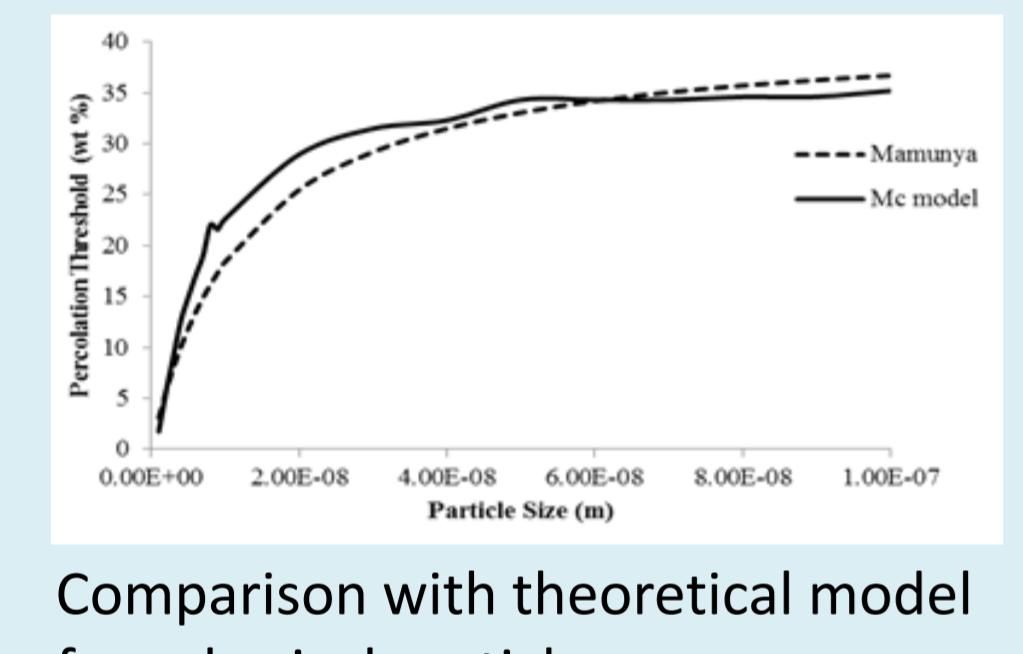
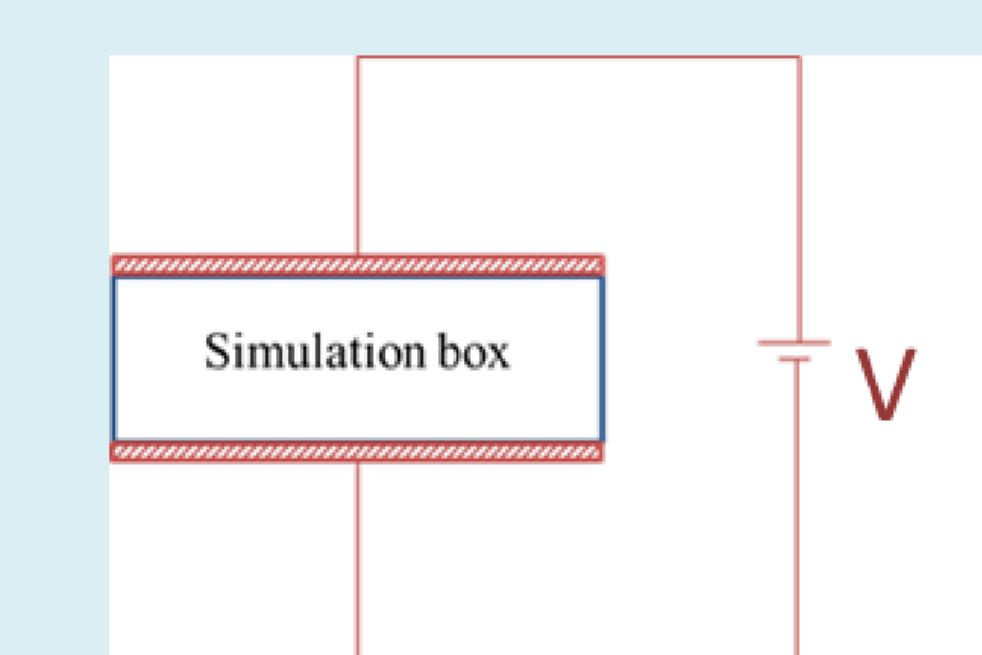
Step 1 – MC simulation performed to find the particle distribution using LJ potential.



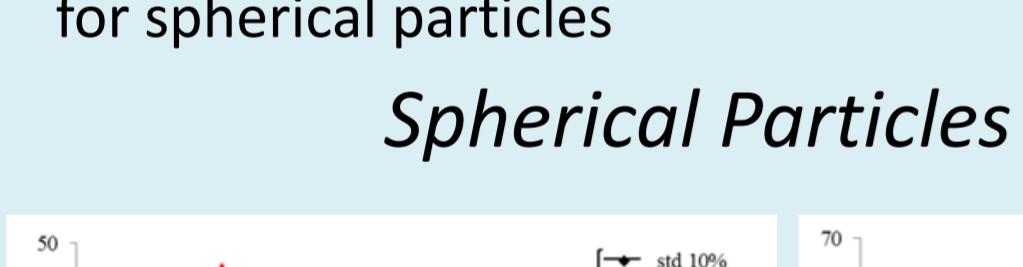
Step 2 – Calculation of the interparticle contact resistance using the particle orientation



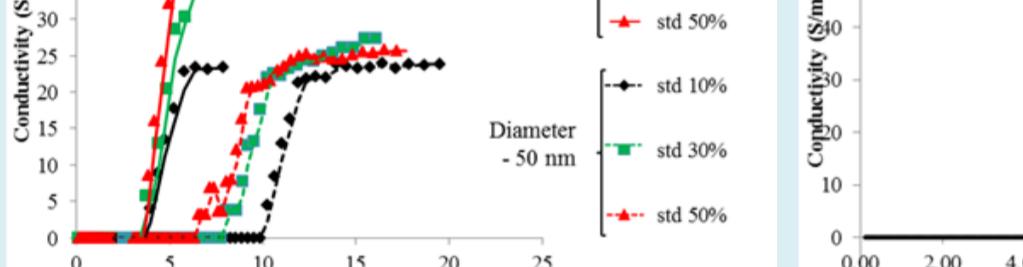
Step 3 – Modelling the resistive network using basic circuit theory and computing the composite conductivity.



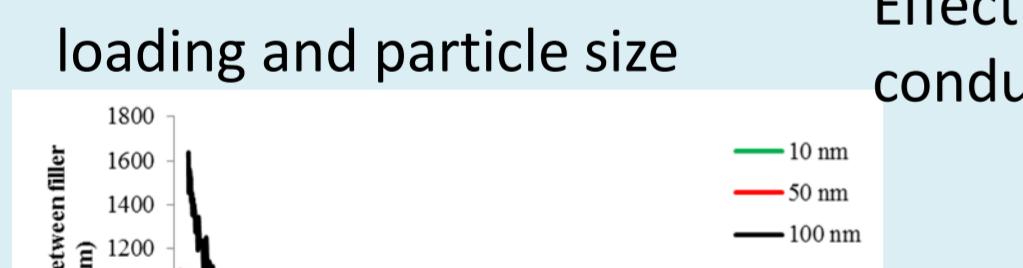
Comparison with theoretical model for spherical particles



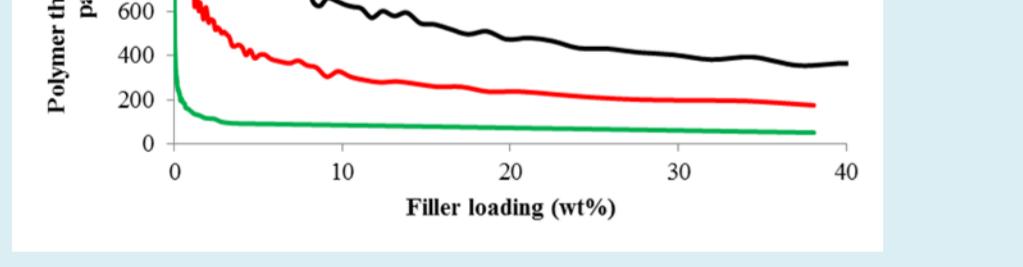
Spherical Particles



Effect of variation of filler loading and particle size



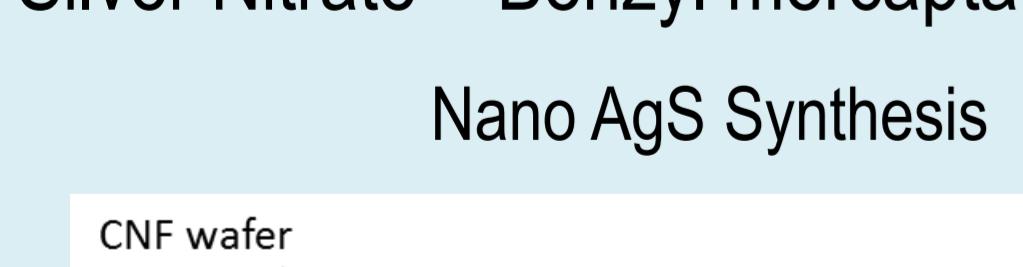
Effect of variation of filler conductivity



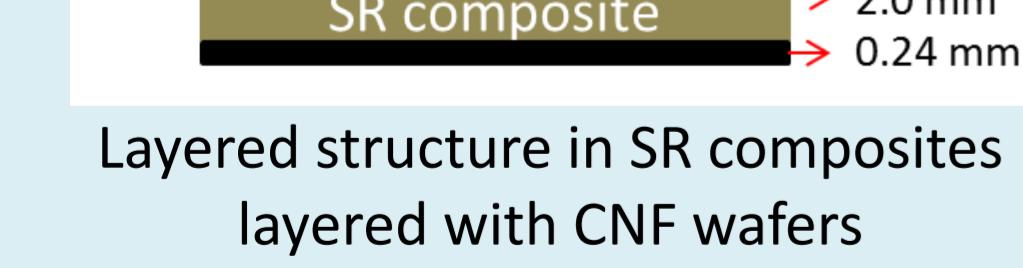
Effect of variation of standard deviation of filler size



Effect of variation of standard deviation of filler size



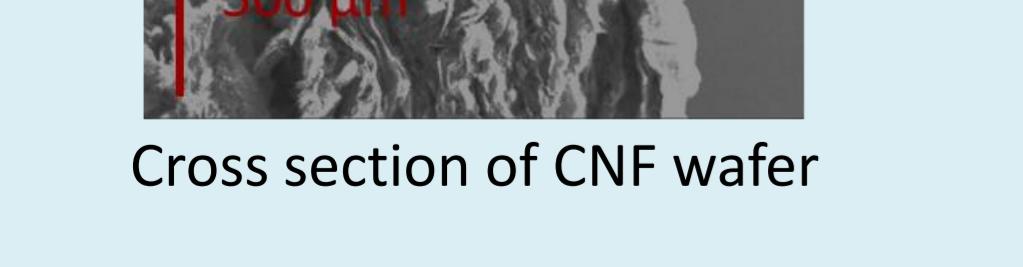
Effect of variation of standard deviation of filler size



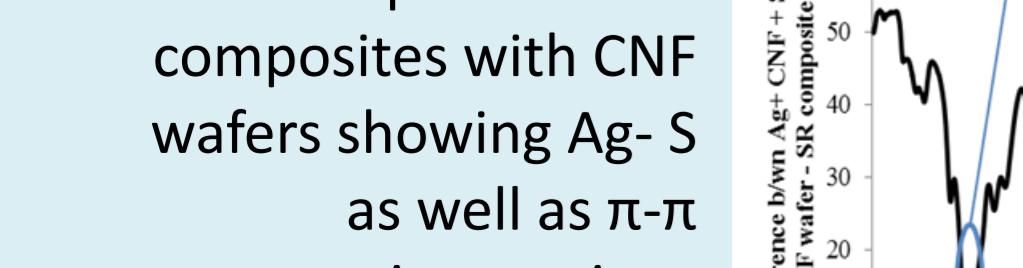
Effect of variation of standard deviation of filler size



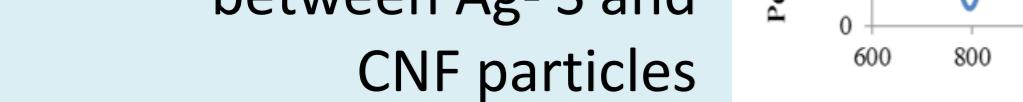
Effect of variation of standard deviation of filler size



Effect of variation of standard deviation of filler size



Effect of variation of standard deviation of filler size



Effect of variation of standard deviation of filler size



Effect of variation of standard deviation of filler size



Effect of variation of standard deviation of filler size



Effect of variation of standard deviation of filler size



Effect of variation of standard deviation of filler size



Effect of variation of standard deviation of filler size



Effect of variation of standard deviation of filler size



Effect of variation of standard deviation of filler size



Effect of variation of standard deviation of filler size



Effect of variation of standard deviation of filler size



Effect of variation of standard deviation of filler size



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Effect of variation of standard deviation of filler size



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Effect of variation of standard deviation of filler size



Effect of variation of standard deviation of filler size



Effect of variation of standard deviation of filler size



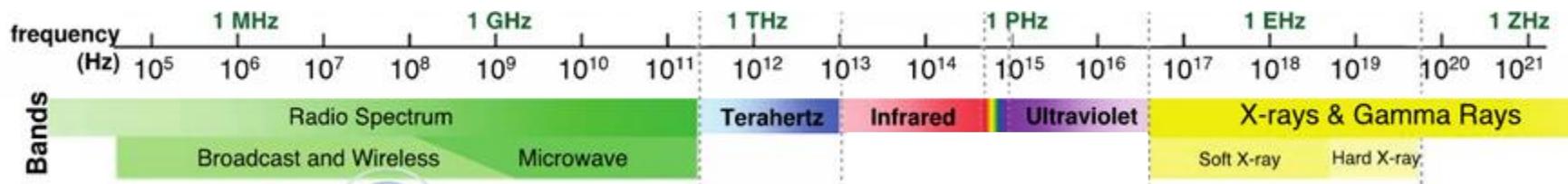
Effect of variation of standard deviation of filler size



Effect of variation of standard deviation of filler size

# Electromagnetic Properties of Carbon based Polymer Nanocomposites for Shielding, Chaffing and Camouflage Applications

Joseph Vimal Vas



# *Stray EM radiation problems and how to solve it- EMI Shielding*

- A power surge due to EMI in one of the fighter planes on **USS Forrestal** triggered a missile to fire on board leading to a fire and 134 lives were lost (Vietnam, 1967).



USS Forrestal (CV-59)

- **Telesat's Anik E1 and E2**-The impulses created by this ESD permanently damaged critical components within the primary gyroscope guidance system control circuitry (Canada, 1994)



Telesat's Anik E1 satellite.

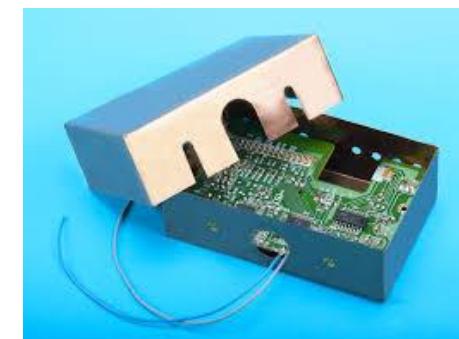
## Different EM Shields



Microwave oven door



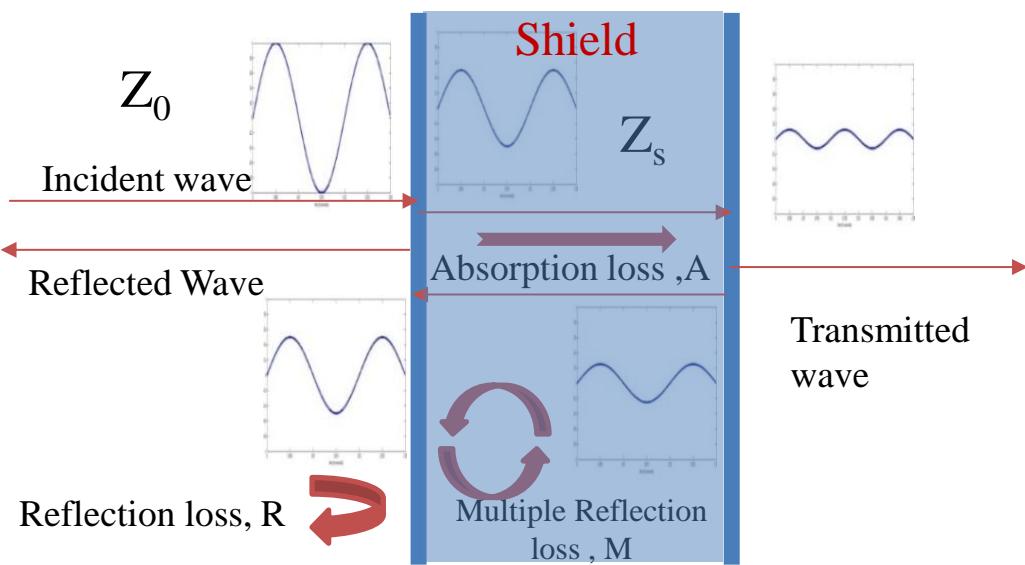
Shielding Chamber (EE, IISc)



Casing of sensitive electronics

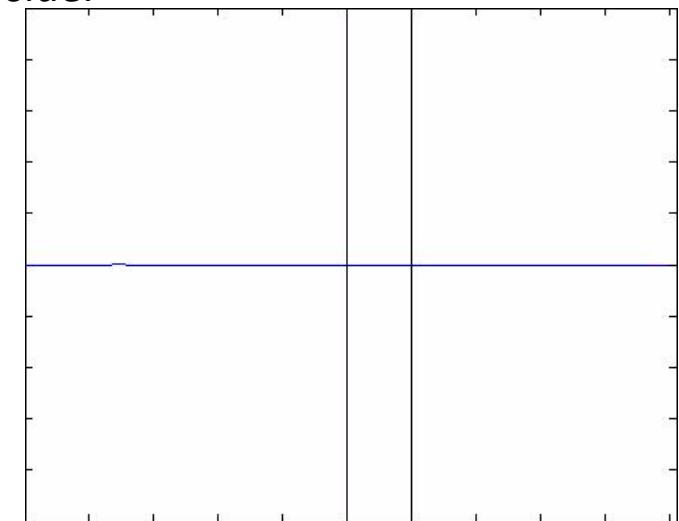
# EM Shields

Shield is any object, usually conducting, that reduces the effect of EM fields on one side from interacting with the devices or circuits on the other side.



$$R = |20 \log| \frac{(Z_0 + Z_s)^2}{4Z_0 Z_s}|$$

$$A = 8.686 k_s d$$



EM propagation in a thin shield

$$M = 20 \log| \frac{(Z_0 + Z_s)^2 - (Z_0 - Z_s)^2 e^{-j2k_s d}}{(Z_0 + Z_s)^2} |$$

$$Z_s = \sqrt{\frac{j\omega\mu_s}{\sigma_s + j\omega\epsilon_s}} \quad k_s = j\omega\sqrt{\mu\epsilon}$$

$\epsilon_s$  – shield permittivity,  $\sigma_s$  – shield conductivity,  
 $\mu_s$  – shield permeability,  $\omega = 2\pi f$

- Shielding effectiveness

$$SE = 20 \log \frac{E_{tn}}{E_{ts}} \text{ dB}$$

$E_{tn}$  and  $E_{ts}$  are the transmitted Electric fields without and with shield respectively.

# Literature Review - Conductivity achieved in Polymer Composites

No.	Filler	Polymer	wt %	Conductivity (S/m)
1	carbon nanotubes	Epoxy	10	1.00E+05
2	Carbon fibre (.16u dia, 100u)	theroplastics	40	2.86E+01
3	Ni filament (.4u)	theroplastics	37	7.14E+03
4	Silver(0.8um)	Polyimidesiloxane	40	6.71E+07
5	CNF (50-200nm)	LCP	15	1.43E+01
6	Carbon fibre (7um)	Epoxy	47	2.22E+01
7	Ni coated Carbon fibre (16nm dia)	PES	7	2.50E+02
8	Carbon black (29nm)	EVA/NR	20	1.00E+02
9	CNT	Shape Memory Polymer	6.7	8.33E+00
10	Expandable graphite	PPS	10	1.00E+02
11	CNT	Epoxy	1	1.00E+03
12	MWCNT	Silicone	1.5	1.00E-03

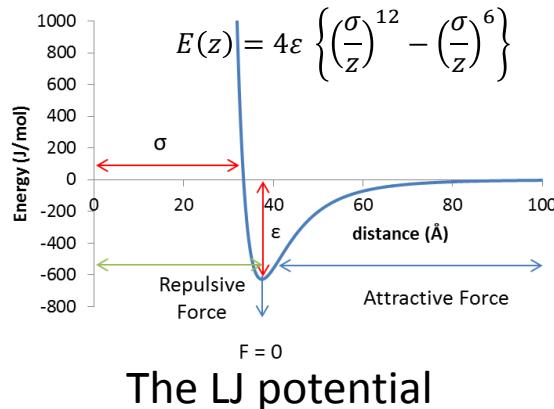
## Conductivity

- Carbon –  $1.28 \times 10^5$  S/m
- Silicone rubber –  $3.85 \times 10^{-19}$  S/m
- Copper -  $5.85 \times 10^7$  S/m

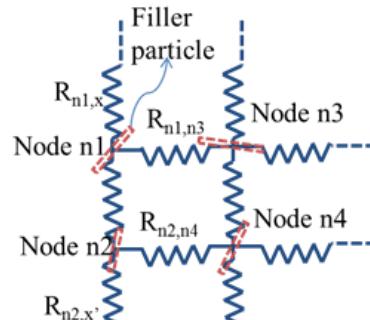
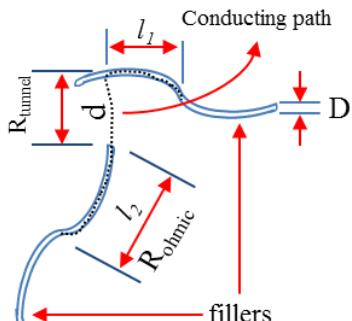


# Monte Carlo Simulations for Conducting Polymer Composites

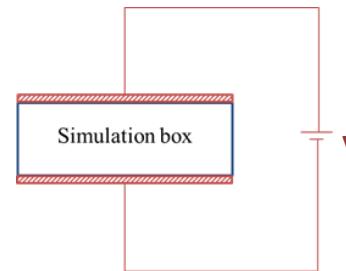
Step 1 – MC simulation performed to find the particle distribution using LJ potential.



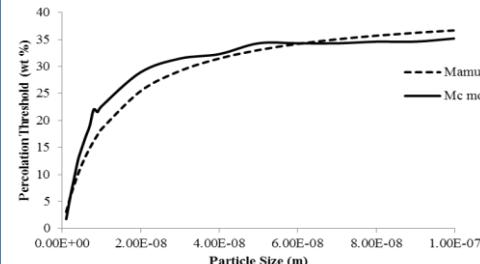
Step 2 – Calculation of the interparticle contact resistance using the particle orientation



Step 3 - Modelling the resistive network using basic circuit theory and computing the composite conductivity.

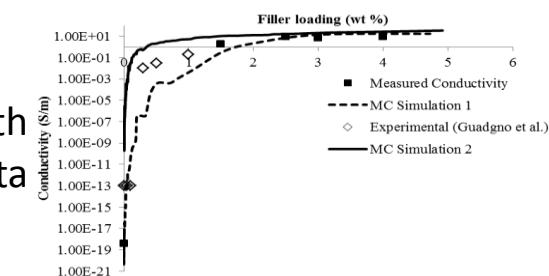


## Validation of the model



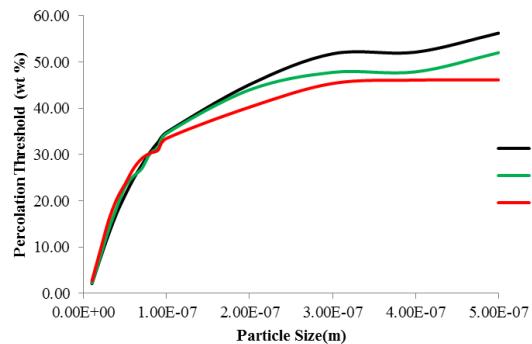
Comparison with theoretical models

## Comparison with experimental data

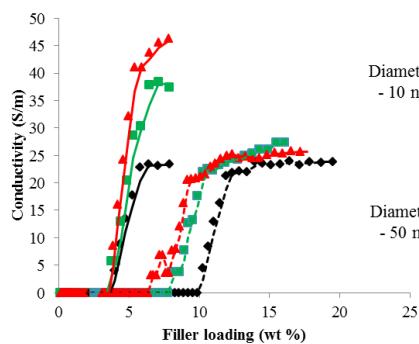


# Monte Carlo Studies on Spherical and Rod like Particles

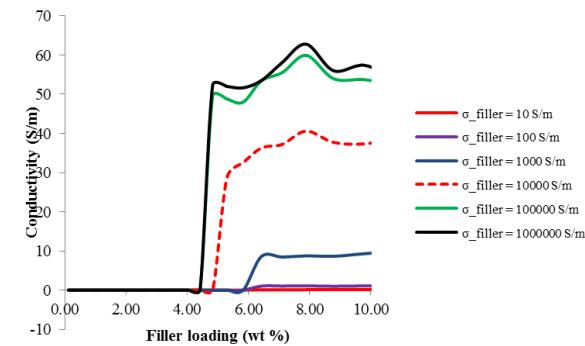
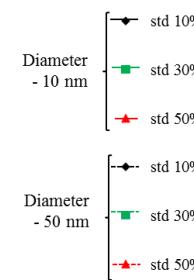
## Composites with spherical particles



Percolation vs. particle size

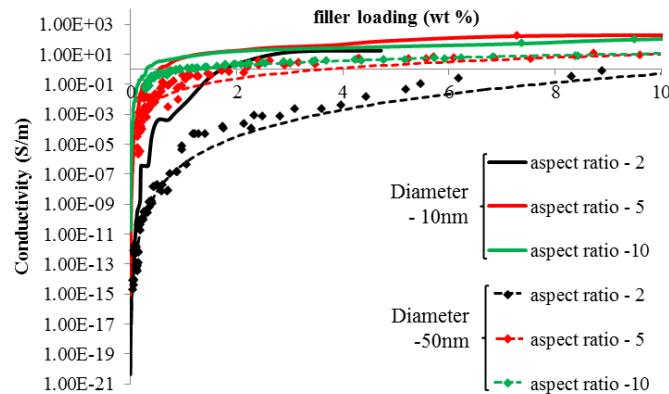


Conductivity vs. particle size



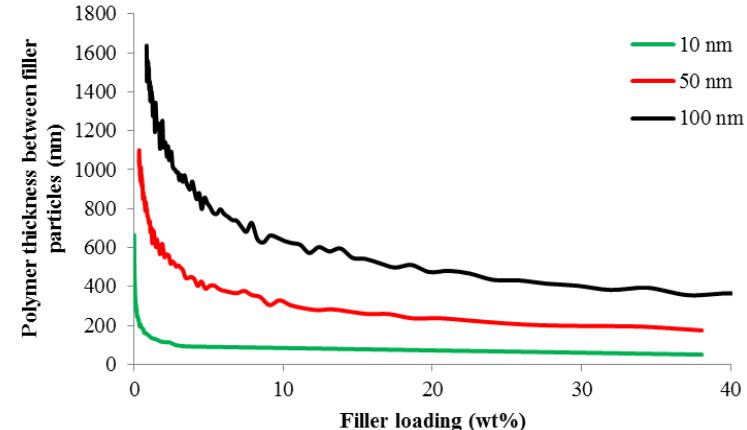
Variation of particle conductivity

## Composites with rod like particles



Conductivity vs. particle size

## Conductivity Limitation



Interparticle distance vs filler loading

# *Synthesis of Conventional Composites*

## Nano composites synthesis

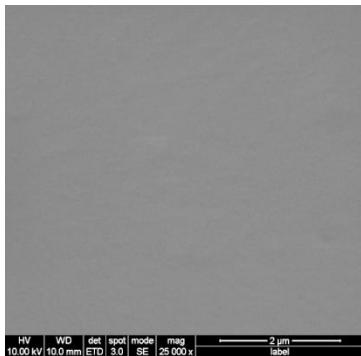
RTV SR – Polymer + Nanofillers + Solvent

Ultrasonication

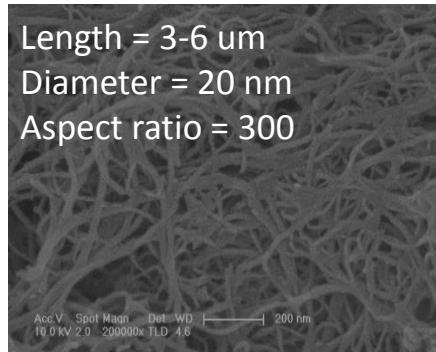
RTV filler mixture + Pt Catalyst

Curing

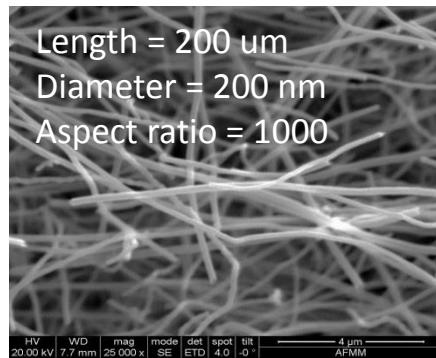
Nano filled SR



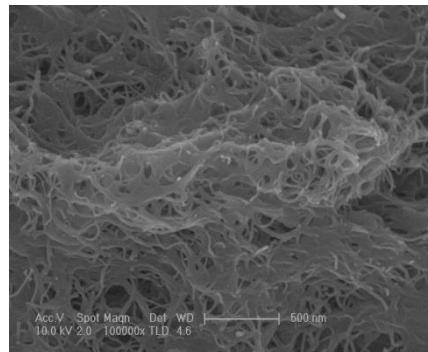
SEM of Silicone  
Rubber



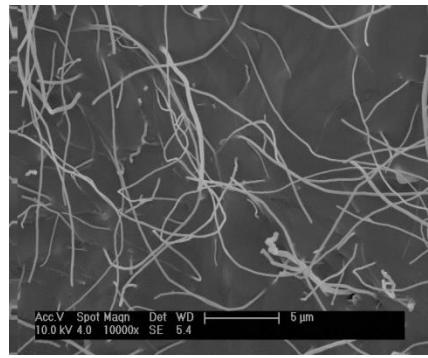
SEM of MWCNT



SEM of CNF



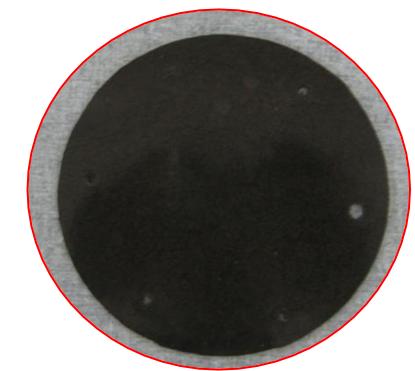
MWCNT-SR Composite



CNF-SR Composite



Mold



SR filled with nano carbon

# Synthesis of SR composites layered with CNF wafers

Silver Nitrate + Benzyl mercaptan + Solvent  
Nano AgS Synthesis

Magnetic Stirrer

Ultrasonication

Nano AgS + CNF

Ultrasonication

Vacuum filtration

CNF wafer

CNF wafer



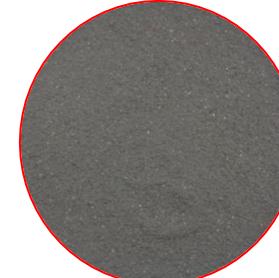
2.0 mm  
0.24 mm



Initial mixture



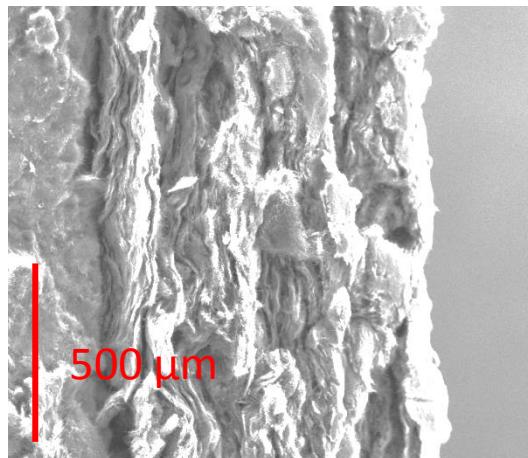
Nano AgS



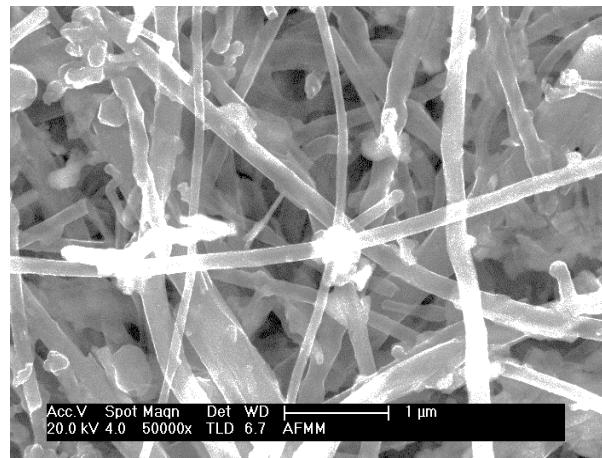
CNF wafer  
 $\sigma = 1320 \text{ S/m}$



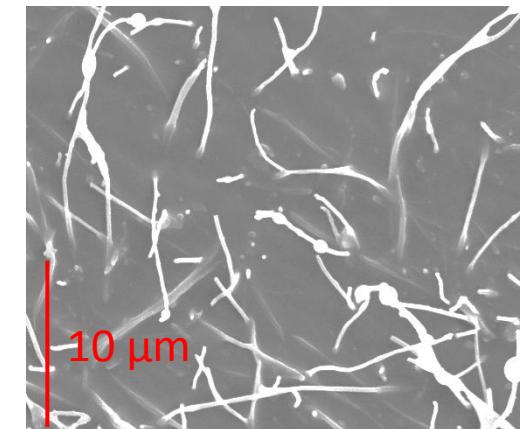
SR composites layered with CNF wafer



SEM image of cross section of CNF wafer

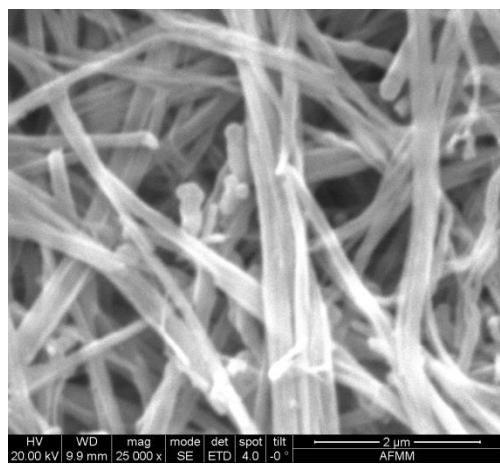


SEM image of the structure of CNF wafer

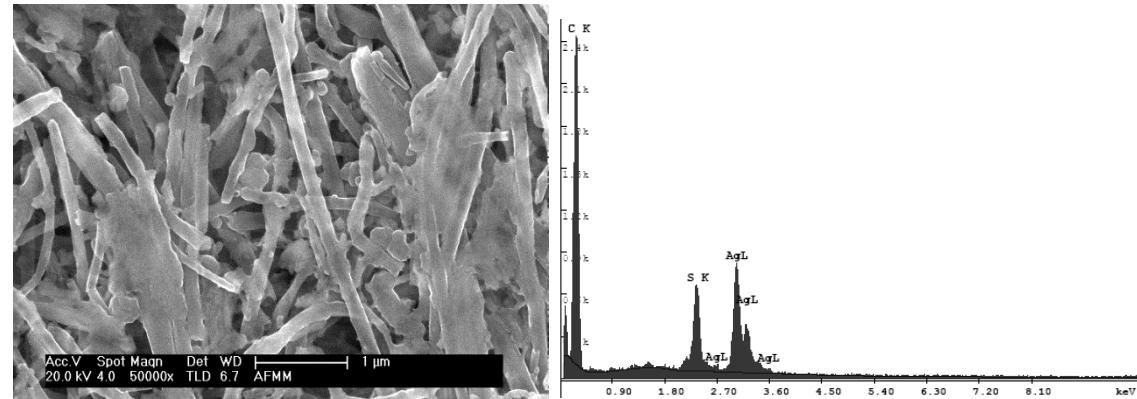


SEM image of CNF wafer- unf  
SR composite

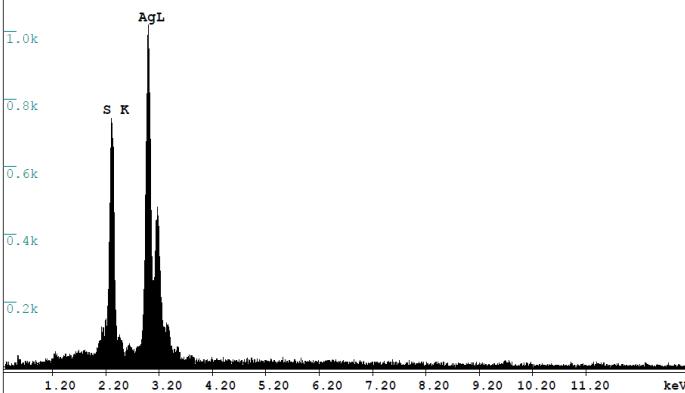
# Results – SEM and EDX studies



Ag- S particles

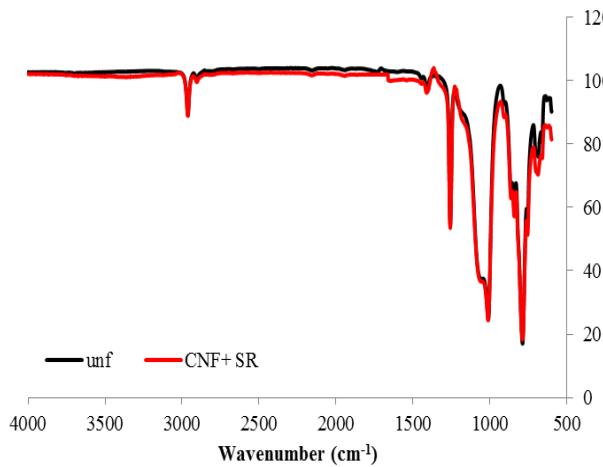


CNF -Ag- S complex

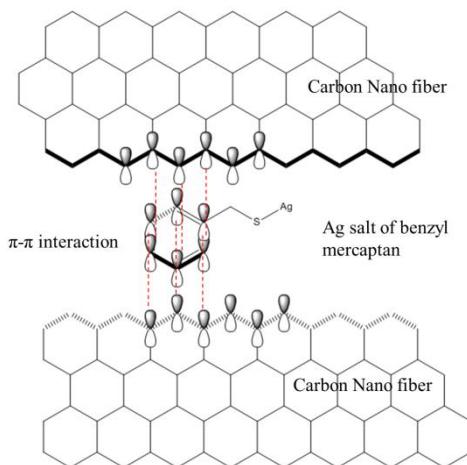


No	Sample Type	C	O	Si	Ag	S
1	unfilled	54.32	17.3	46.16		
2	CNF filler	89.47	7.4			
3	Ag-S particles				57.2	42.7
4	CNF wafer	92.84			2.66	2.36
5	CNF wafer- SR composites	70.26	12.8	15.55	0.43	0.48

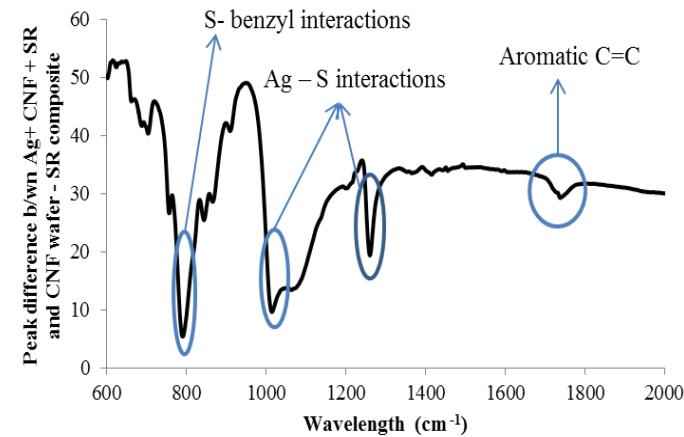
# Results – FTIR



FTIR spectra of unfilled and CNF filled SR



Structure of the CNF wafer



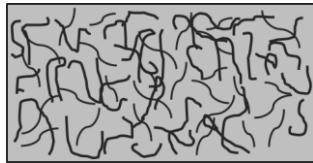
Difference between the FTIR spectra of Ag-CNF binary composites and SR composite layered with CNF wafer

No	Group	Wave number (cm <sup>-1</sup> )	Material
1	-C = C- (Alkenyl group)	1680-1620	CNF interactions
2	-C = C - (Aromatic)	1700-1500	AgS nanoparticle
3	-Ag – S	1008,1355	
4	C <sub>6</sub> H <sub>5</sub> –CH <sub>2</sub> - X	690,710,730-770	

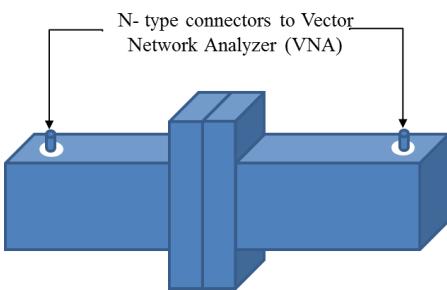
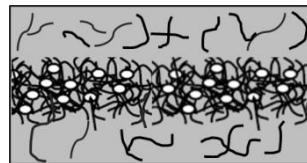
# Conductivity and Permittivity Measurements

- The CNF wafer has a conductivity of 1360 S/m
- Both the conventional composites turned conducting at filler loadings less than 3%.

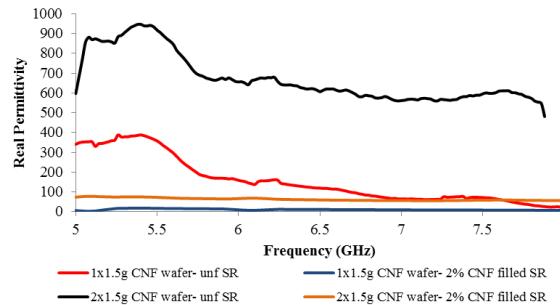
Conventional Composite



SR Composite layered with CNF wafer



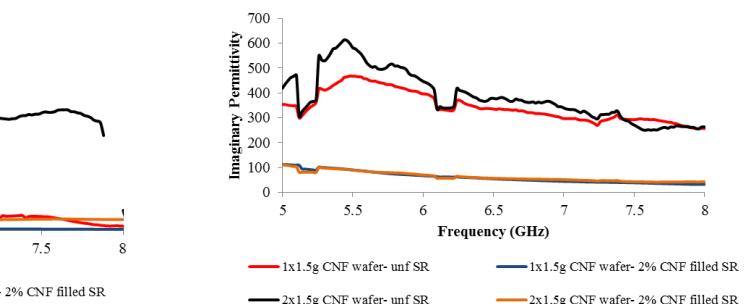
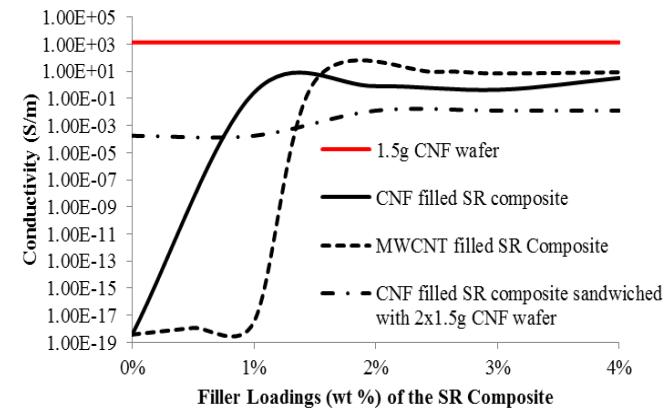
Permittivity measurement as per ASTM D5568



Real Permittivity

- Permittivity of conventional composites < 10
- SR composites layered with CNF wafers showed very high real and imaginary permittivities

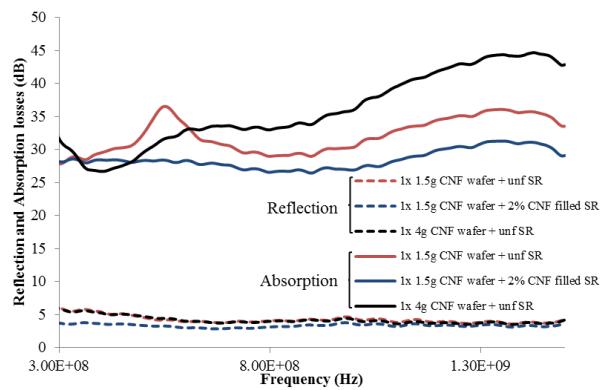
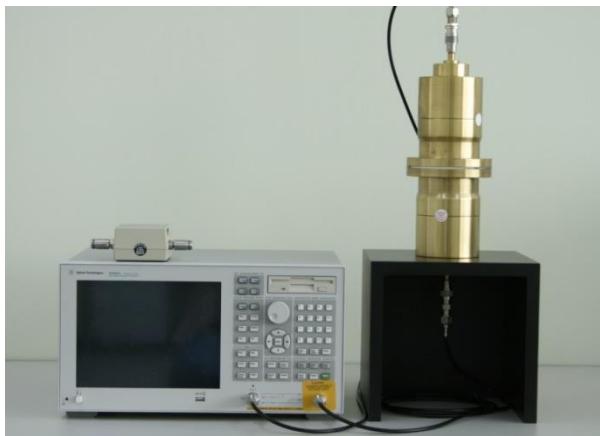
Conductivity vs filler loading for different composites



Imaginary Permittivity

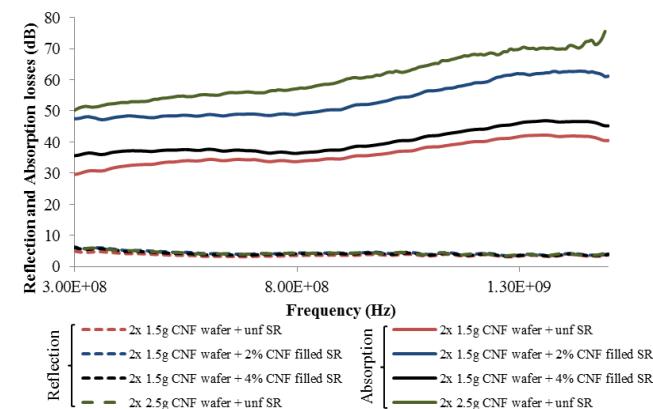
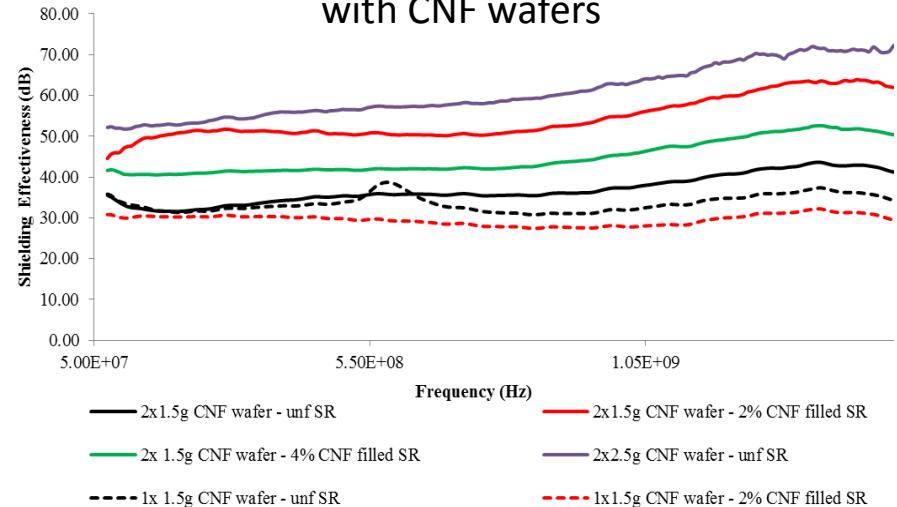
# Shielding Effectiveness of different composites

ASTM D4935 measurement set up  
fabricated in the lab



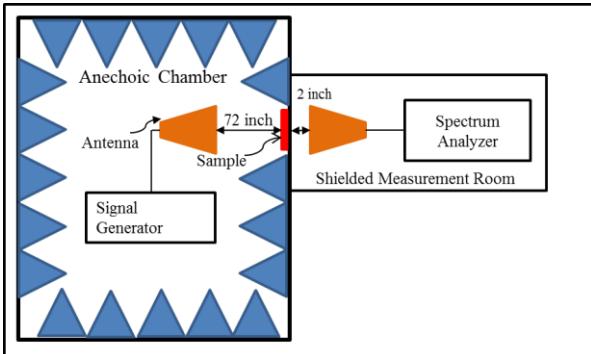
Reflection and absorption losses of SR  
composites with 1 CNF wafer layer

Shielding Effectiveness of SR composites layered  
with CNF wafers



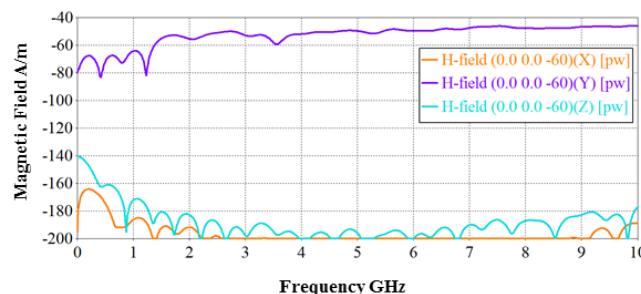
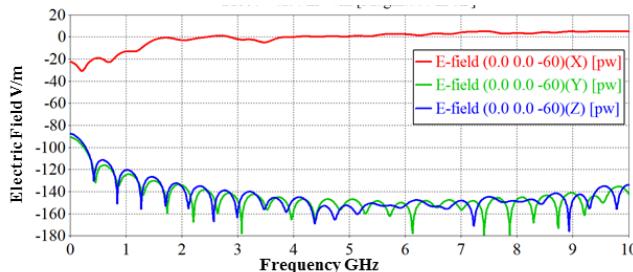
Reflection and absorption losses of SR  
composites with 2 CNF wafer layers

# Setup used for the Anechoic Chamber measurements



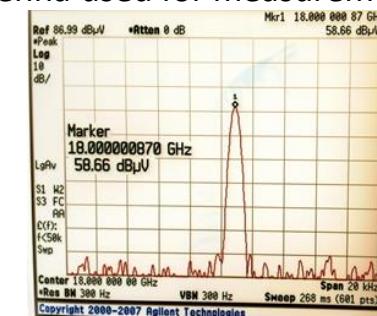
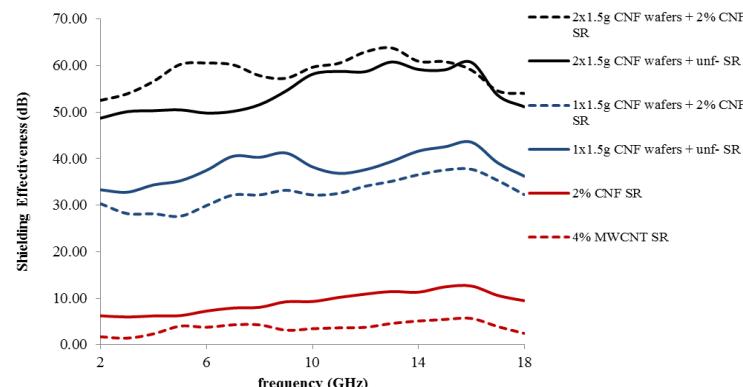
Radiated field

Horn antenna used for measurement

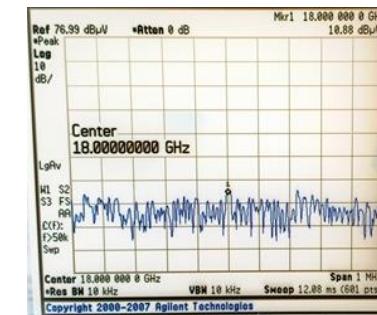


Electric and Magnetic Fields Experienced by the sample

Shielding Effectiveness  
Measured in the 2-18 GHz  
frequency range



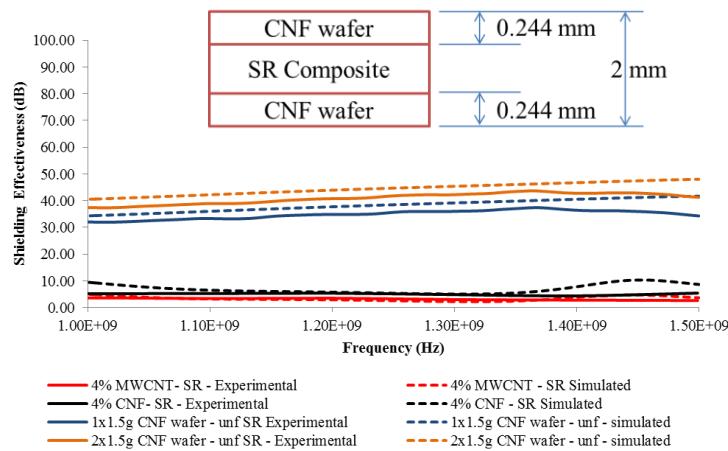
Measured field in the absence of the sample



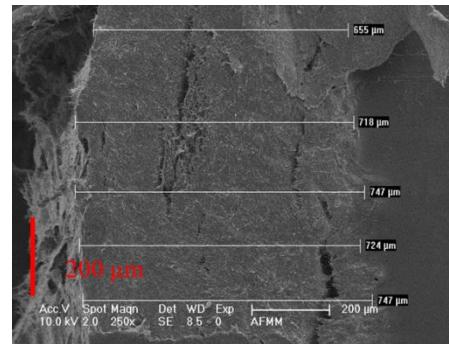
Measured field with the sample

# EM Modelling of Layered Composites

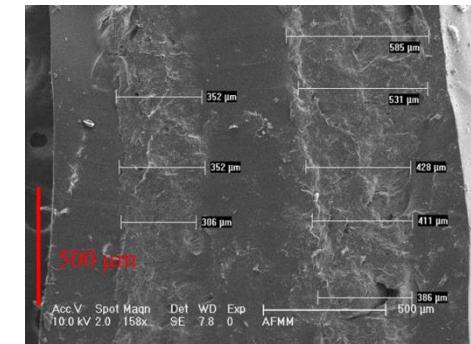
Sample Type	Absorption (dB)	Thickness (mm)
1x1.5g CNF wafer	-	0.244
1x1.5g CNF wafer - unf SR	31.32	0.729
1x1.5g CNF wafer - 2% CNF+ SR	28.61	0.697
2x1.5g CNF wafer - unf SR	34.93	0.752
2x1.5g CNF wafer - 2% CNF+ SR	52.22	1.942
2x1.5g CNF wafer - 4% CNF + SR	43.98	0.675



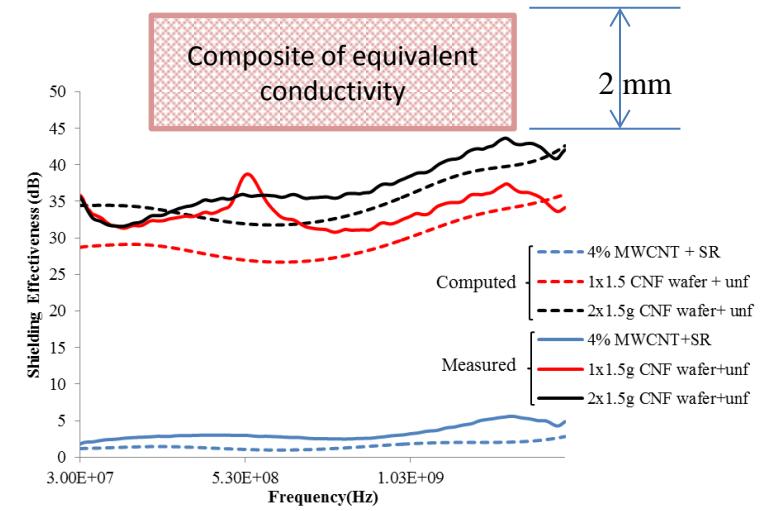
Prediction of SE based on 3 layer model



CNF wafer with 1 wafer



CNF wafer with 2 wafer



Prediction of SE based on permittivity

# *Conclusions*

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## Studies on Conventional Composites

- The conventional conducting polymers with MWCNT and CNF filled SR had very less conductivity and shielding effectiveness.
- The shielding effectiveness of the conventional conducting composites were not suitable for shielding applications.

## Studies on SR composites with CNF wafers

- Composites were synthesized with highly conducting CNF wafers.
- Even though the bulk conductivity of the composites were low, the CNF wafer composites showed good shielding behavior.
- This was because of the highly conducting CNF wafer layers present in the composite.

## Waveguide measurements

- The shielding behavior, reflection loss, absorption loss was measured in the frequency range 5-18 GHz.
- Samples showed trends similar to the Anechoic Chamber method and the coaxial fixture method for low frequency.
- The reflection loss of all the composites were low but increased with CNF content.
- This could be because of the increase in real permittivity due to increased carbon content.
- The large absorption loss was due to the higher imaginary permittivity of the layered composites.

## Shielding, Reflection and Absorption Measurements

- The set up used was designed such that the samples experienced a TEM wave.
- The conventional composites showed very low shielding effectiveness.
- The SR composites with different layers of CNF wafers had very high shielding effectiveness
- All the composites showed very low reflection loss
- The shielding behavior was mainly attributed to the absorption loss
- The absorption loss depends on the thickness of the CNF wafers in the SR matrix
- The reflection loss marginally increased with CNF content.

